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On: July 18, 2005

By: Rajashree Mohabeer  
Rajashree Mohabeer

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**Attorney Docket No.: NEKO 19.481 (100806-00091)**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Inventor: Kazunori KISHIMOTO

Serial No.: 10/083,447

Filed: February 26, 2002

Title: **METHOD OF TESTING A SEMICONDUCTOR  
INTEGRATED CIRCUIT AND METHOD AND  
APPARATUS FOR GENERATING TEST PATTERNS**

Examiner: John P. Trimmings

Group Art Unit: 2133

July 18, 2005

Mail Stop AF  
Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

SIR:

In response to the Office Action mailed on April 29, 2005, the period for responding thereto having been set to expire after July 29, 2005, please amend the subject application as follows.